

# REPORT: TRANSMISSION ELECTRON MICROSCOPY (TEM) - ON REPAIR

## 1. Title

Transmission Electron Microscopy (TEM) Analysis of Nanomaterials (Instrument Under Repair)

## 2. Objective

To examine the ultrastructural morphology and particle size of nanomaterials using TEM, noting that the instrument is currently under repair.

## 3. Introduction

Transmission Electron Microscopy (TEM) is a high-resolution imaging technique that transmits electrons through a specimen to create a high-magnification image. It is commonly used for studying the structure of materials at the atomic level.

## 6. Results / Status

Analysis could not be completed due to ongoing repair of TEM instrument.

## 7. Notes

Sample prepared and stored; analysis will be conducted once the TEM is functional.